## Notice of References Cited Application/Control No. 10/598,625 Examiner TAN Q. NGUYEN Applicant(s)/Patent Under Reexamination KIRK ET AL. Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,587,781	07-2003	Feldman et al.	701/117
*	В	US-6,577,946	06-2003	Myr, David	701/117
*	С	US-6,708,085	03-2004	Yamane et al.	701/1
*	D	US-6,810,321	10-2004	Cook, Fred S.	701/117
*	Е	US-7,188,026	03-2007	Tzamaloukas, Assimakis	701/200
*	F	US-7,228,224	06-2007	Rosen et al.	701/117
*	G	US-7,269,507	09-2007	Cayford, Randall	701/208
*	Η	US-2003/0225668	12-2003	Goto et al.	705/37
*	I	US-2004/0010368	01-2004	Scott, Logan	701/213
*	J	US-2006/0122846	06-2006	Burr et al.	705/001
	K	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
*	Ν	CA2429659	06-2002	CA	Atkinson et al.	
*	0	CA2391605	06-2000	CA	Lang	
*	Ρ	WO0225617	03-2002	wo	Lapidot	
	Ø					
	R					
	Ø					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	x	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.